

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 251154US2SRDX		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Toru TOJO, et al.			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
IA	AA	5,572,598	11/05/96	Mark J. WIHL, et al.			
IA	AB	5,563,702	10/08/96	David G. EMERY, et al.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
IA	AO	2002-501194	01/15/02	Japan		X	
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	Yasutaka MORIKAWA, et al., "PERFORMANCE OF CELL-SHIFT DEFECT INSPECTION TECHNIQUE", Proceedings of SPIE, Photomask and X-Ray Mask Technology IV, Vol. 3096, 1997, pgs. 404 - 414.					
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner				/Isiaka Akanbi/		Date Considered 05/26/2006	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							